Notice of Allowability	Application No.	Applicant(s)
	10/696,742	DEN BOEF ET AL.
	Examiner	Art Unit
	Amanda H. Merlino	2877
The MAILING DATE of this communication apperall claims being allowable, PROSECUTION ON THE MERITS IS therewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIPORT of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communicatio GHTS. This application is subject	oplication. If not included n will be mailed in due course. THIS
		
2. The allowed claim(s) is/are <u>2,8-18,20 and 21</u> .		
 Acknowledgment is made of a claim for foreign priority un a) ☐ All b) ☐ Some* c) ☐ None of the: 	nder 35 U.S.C. § 119(a)-(d) or (f).	
1. Certified copies of the priority documents have	been received.	
2. Certified copies of the priority documents have	been received in Application No	:
3. Copies of the certified copies of the priority doc	cuments have been received in this	national stage application from the
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" on noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
 A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give 		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	t be submitted.	
(a) I including changes required by the Notice of Draftspers	on's Patent Drawing Review (PTO	-948) attached
1) hereto or 2) to Paper No./Mail Date		
(b) including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the	Office action of
Identifying indicia such as the application number (see 37 CFR 1, each sheet. Replacement sheet(s) should be labeled as such in the		
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I 		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	5. ☐ Notice of Informal l 6. ☑ Interview Summan Paper No./Mail Da	
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0		
Paper No./Mail Date 4. ☐ Examiner's Comment Regarding, Requirement for Deposit	8 🖾 Examiner's Statem	ent of Reasons for Allowance
of Biological Material	9. Other	Gregory Towley Str. Supervisor Patent Examiner
U.S. Patent and Trademark Office PTOL-37 (Rev. 7-05) No	otice of Allowability	Part of Paper No./Mail Date 20060810
1. 1.02.07 (1.04. 1-00)	AND DI ANDREDHILY	1 alt of 1 apol 140./mail Date 20000010

Application/Control Number: 10/696,742 Page 2

· Art Unit: 2877

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Guillermo E. Baeza on 8/7/06.

The application has been amended as follows:

- a) on line 5 of claim 8, "and" has been deleted;
- b) on line 7 of claim 8, --; and adjusting the lithographic apparatus based upon the derived information, -- has been added after "apparatus";
 - c) on line 5 of claim 10, "and" has been deleted;
- d) on line 7 of claim 10, --; and adjusting the lithographic apparatus based upon the derived information, -- has been added after "apparatus".

Reasons for Allowance

As to claims 2, 8 and 9, the prior of record, taken alone or in combination, fails to disclose or render obvious an inspection method for deriving, from the reflection spectrum, information indicative of an amount of at least one type of aberration of the lithographic apparatus comprising the steps of forming, at a surface of the substrate, a test structure corresponding to the test pattern wherein the test pattern comprises a hexagonal array of dots, and said information includes information indicative of three-wave aberrations, in combination with rest of the limitations of claim 8.

As to claims 10-18 and 20-21, the prior of record, taken alone or in combination, fails to disclose or render obvious an inspection method for deriving, from the reflection spectrum, information indicative of an amount of at least one type of aberration of the lithographic apparatus comprising the steps of forming, at a surface of the substrate, a test structure corresponding to the test pattern wherein the test pattern comprises first, second, and third structures having a common basis symmetric form, and wherein said first and second structure have equal but opposite asymmetric deviations from the common basis symmetric form, in combination with the rest of the limitations of claim 10.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Amanda H Merlino whose telephone number is 571-272-2421. The examiner can normally be reached on Monday and Thursday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J Toatley, Jr. can be reached on 571-272-2800 ext 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/696,742

Art Unit: 2877

Page 4

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Amanda H Merlino Amanda

upervisory Patent Examiner